		Application/Control No.	Applicant(s)/Patent Under Reexamination
Notice of References Cited		09/392,106	PHILLIPS ET AL.
		Examiner	Art Unit	Page 1 of 1
		Alain L. Bashore	3624	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,088,676 A	07-2000	White, Jr., Halbert L.	705/1
	B	US-6,363,333 B1	03-2002	Deco et al.	702/191
	C	US-6,532,449 B1	03-2003	Goertzel et al.	705/35
	D	US-6,289,321 B1	09-2001	Suganuma, Shigeru	705/36
	E	US-6,473,084 B1	10-2002	Phillips et al.	345/440
	F	US-6,606,615 B1	08-2003	Jennings et al.	706/45
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Meade et al; "Technological Forecasting- Model Selection, Model Stability, and Combining Models"; August 1998; Managemen Science; 44th ed; pp. 1115-1130.
	V	Everitt (ed); "The Cambridge Dictionary of Statistics"; Cambridge University Press; 1998; pp339-340.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.